LT2000E Touch Panel Tester

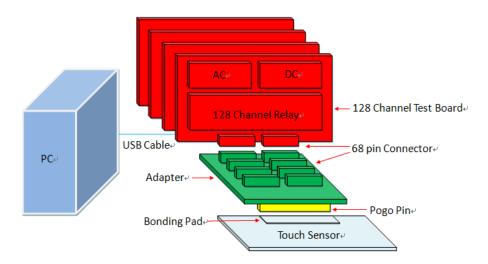


LT2000E Touch Panel Tester is designed to test the touch sensor electrical characteristic using.LT2000E can test touch sensor's Open, Short, Wire resistance, Insulation resistance and Node capacitance, which can measure the Insulation resistance to 1000M ohm, and Node capacitance can be measured to 0.1 pF.

LT2000E has a fast measurement function, Test time for each Short test is 6 ms, each Wire resistance test is 11 ms, each Insulation resistance test is 33 ms, and each Node capacitance test is 10ms. LT2000E can be integrated to be a manual tester, that is the lowest cost way to test touch sensor, can also be integrated a automatic tester with CCD alignment that could improve production testing speed.

LT2000E will save test value after Touch Sensor is tested, and also provide 2D and 3D statistic chart.

LT2000E Tester Architecture:



LT2000E 512 Channel Touch Sensor Tester

LT2000E Main Function:

- Test Channel: 128/256/384/512 Test Channels •
- Can do test for Open, Short, Wire resistance, Insulation resistance and Node

capacitance.

- Can measure the Insulation resistance to 1000M ohm, and can measured Node capacitance to 0.1 pF.
- Fast measure function: each Short test is 6 ms, each Wire resistance test is 11 ms, each Insulation resistance test is 33 ms, each Node capacitance test is 10 ms.
- Can be integrated to be a manual tester, or can also be integrated to be a automatic tester with CCD alignment.
- With test program auto editing function, can finish one test program editing within 30 sec.
- Provide auto calibration for Parasitic capacitor of adapter.
- With test setting function for Fail Stop, Test All and Repeat Fail Stop.
- Can display test time for all test items and for each individual test item.
- Select item for repeat test function, can do repeat test, can to stability verification for touch sensor.
- Can choice specify test items for testing, provide engineering analysis using.
- Auto save for touch tensor test value, and also provide 2d and 3D statistic chart.

LT2000EManual tester and Automatic tester:



LT2000E 3D statistic Chart of Node Capacitance:

Test Pro	C:\Lt2000\Pr		Operator			Tota	
	TS101(20140 evice:)30901).tps	Lot	: 1		Pas: Fai	
Har	ndler: Default	Т	est Time (r	ns): 14653.	5	Yield	ooj c
Index	Item Name	Standard	High Limit	Low Limit	Meausure	Unit	
124	RI_Y15_Y16	200	N	200.000	679.415	MO	
125	C_X1_Y1	7	9.100	4.900	7.519	pf	Summary
126	C_X1_Y2	7	9.100	4.900	7.067	pf	
127	C_X1_Y3	7	9.100	4.900	6.949	pf	Charles Charle
128	C_X1_Y4	7	9.100	4.900	6.775	pf	ð <u>////////////////////////////////////</u>
129	C_X1_Y5	7	9.100	4.900	6.832	pf	
130	C_X1_Y6	7	9.100	4.900	6.804	pf	Charl
131	C_X1_Y7	7	9.100	4.900	6.497	pf	
132	C_X1_Y8	7	9.100	4.900	6.451	pf	
133	C_X1_Y9	7	9.100	4.900	6.446	pf	
134	C_X1_Y10	7	9.100	4.900	6.822	pf	
135	C_X1_Y11	7	9.100	4.900	6.987	pf	
136	C_X1_Y12	7	9.100	4.900	7.034	pf	
137	C_X1_Y13	7	9.100	4.900	7.006	pf	9.5
138	C_X1_Y14	7	9.100	4.900	7.505	pf	pf.9
139	C_X1_Y15	7	9.100	4.900	8.130	pf	
140	C_X1_Y16	7	9.100	4.900	9.199	pf	
141	C_X2_Y1	7	9.100	4.900	7.307	pf	6.5
142	C X2 Y2	7	9 100	4.900	7 727	nf	2 4 6 8 10 12 14 16 18 20 22 24 26

LT2000E 2D Test Display of Node Capacitance:

	ation	Test Setting To C:\Lt2000\Pr		Operator			Tota	ی ا								Log	g an	d Su	mm	ary									100		
Test	t Prog Dev	TS101(20140		Lot			Pase	¢ġ	C RIX	C	RIY (RS RS	< C	RS Y	C	CGno	1	C Sur	face	(€ To	ower										
Handler : Default Tes				est Time (ms): 14653.5			Yield	201 32	Ħ	Ш	TTT	ŦĦ	T			Π				Ĥ	Π	П	П	H	H	ŦŦ	Ŧ	Ŧ	H	Π	
Inc	dex	Item Name	Standard	High Limit	Low Limit	Meausure	Unit	30																		+	-	-	#	Ħ	Ħ
/ 12	24	RI_Y15_Y16	200	N	200.000	679.415	MO	Summary 82																				1	Ħ	tt	Ħ
V 12	25	C_X1_Y1	7	9.100	4.900	7.519	pf	8 26					++						++					+++	H	+	++	++	++-	++	+
V 12	26	C_X1_Y2	7	9.100	4.900	7.067	pf	Su																	H	_		#	-	F	
V 12	27	C_X1_Y3	7	9.100	4.900	6.949	pf	24 22 22					+				+		+	++		+		H	H	+	++	+	+	+	+
V 12	28	C_X1_Y4	7	9.100	4.900	6.775	pf	년 ²²																	H	-	+	-	#	F	Ħ
V 12	29	C_X1_Y5	7	9.100	4.900	6.832	pf	8 20																			+	+	+		
V 13	30	C_X1_Y6	7	9.100	4.900	6.804	pf	and the second s																\square				-	+	-	-
V 13	81	C_X1_Y7	7	9.100	4.900	6.497	pf																								
V 13	32	C_X1_Y8	7	9.100	4.900	6.451	pf	16 07																\square							\square
V 13	33	C_X1_Y9	7	9.100	4.900	6.446	pf	-14																							
V 13	34	C_X1_Y10	7	9.100	4.900	6.822	pf	12													++	++		+++	+++	++		++	++-		+
V 13	85	C_X1_Y11	7	9.100	4.900	6.987	pf																		CTT		-	1	#	Ħ	Ħ
V 13	36	C_X1_Y12	7	9.100	4.900	7.034	pf	10																+++	\square	+	++	++	++-	+	+
V 13	37	C_X1_Y13	7	9.100	4.900	7.006	pf	8																			#	#	-	F	
V 13	88	C_X1_Y14	7	9.100	4.900	7.505	pf	6																+++			++	+		+	H
V 13	39	C_X1_Y15	7	9.100	4.900	8.130	pf	4																	H	-	-	-	-	-	H
V 14		C_X1_Y16	7	9.100	4.900	9.199	pf																				++	+	\pm		\square
V 14		C_X2_Y1	7	9.100	4.900	7.307	pf	2																H	H	+	-	+	Ŧ	H	H
V 14		C X2 Y2	7	9 100	4 900	7 227	nf	0																			+	+	1		
]	Fail	Yiel	d 86.3	3 %			Pas	0 1 2		5678	9 10	11121	31415	51617	18192		22324: Clo		27282	9303-	1323	33435	3637:	38394	10414	2434	14546	54748	4950	515
PT 128	En	igineering Mode	1			Test /	All Item													-											
-					Ø		٢		11		11100	-	53		-	-	5			-	-		100 2	ЩЩ.)			20124	英			年0

LT2000E Specification:

1	Main Function	Measure Open Short Wire resistance Insulation resistance								
		and Node capacitor for touch sensor.								
2	Test Channel	128/256/384/512 Channels								
3	Test Items	Short :								
		Short between 2 wires of Rx ITO(or Tx ITO)								
		Open :								
		Open at each wire of Rx ITO(or Tx ITO)								
		Wire Resistance:								
		each wire resistance on Rx ITO(or Tx ITO)								
		Insulation Resistance:								
		Resistance between wires of Rx ITO (or Tx ITO)								
		Node Capacitance:								
		Capacitance between wires of Rx ITO and Tx ITO								
		Wire Capacitance :								
		Capacitance between wire of Rx ITO(or Tx ITO)								
4	Test Time	Each Short test is 6 ms								
		Each Wire resistance test is 11 ms								
		Each Insulation resistance test is 33 ms								
		Each Node capacitor test is 10 ms								
5	Measure Short	Range : 1 ohm ~ 1M ohm , Accuracy: +/- 0.5 ~15% of								
		Range								
6	Measure Wire	Range : 1 ohm ~ 10M ohm , Accuracy: +/- 0.5~1% of								

	Resistance	Range								
7	Measure Insulation	Range : 1 ohm ~ 1000M ohm , Accuracy: +/- 1~10% o								
	Resistance	Range								
8	Measure C	Range: 0.1 pF ~ 200 pF \cdot Accuracy: +/- 1 ~ 3% of Range								
9	Calibration Method	Calibrated by Agilent LCR Meter								
10	Operating System	Microsoft Windows XP/Win7/Win8(32 bits)								
11	Weight	7.3 Kg(512 Channels, With power supply)								
12	Dimension	442(W)*221(D)*161(H)mm								
13	Power Supply	110/240 VAC • 50~60Hz • 1.6A								

Legend Legend Technic Co., Ltd.

Address: 10F.-2, No.7, Sec. 3, New Taipei Blvd., Xinzhuang Dist., New Taipei City 242, Taiwan (R.O.C.) TEL: +886-2-85227068 FAX: +886-2-85227058

Web Site: www.legendtech.com.tw E-mail:sales@legendtech.com.tw